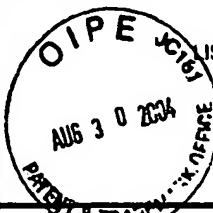


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2417	SERIAL NO. 10/689,958		
 <p style="margin-top: 10px;">LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)</p>				APPLICANT: Cem Basceri			
				FILING DATE October 20, 2003		GROUP 2012-2824	
<b>U.S. PATENT DOCUMENTS</b>							
*Examiner's Initials	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
BEO	AA	4,086,074	04/78	Minot et al.	—		
	AB	4,622,735	11/86	Shibata	—		
	AC	4,683,645	08/87	Naguib et al.	—		
	AD	4,693,910	09/87	Nakajima et al.	—		
	AE	4,766,090	08/88	Coquin et al.	—		
	AF	5,099,304	03/92	Takemura et al.	—		
	AG	5,236,865	08/93	Sandhu et al.	—		
	AH	5,444,024	08/95	Anjum et al.	—		
BEO	AI	5,470,784	11/95	Anjum et al. <i>Coleman et al.</i>	—		
<b>FOREIGN PATENT DOCUMENTS</b>							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
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<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
BEO	AM	ABSTRACT: Basceri et al., Atomic Layer Deposition for Nanoscale CU Metalization, 10 pages (pre-April 2004).					
BEO	AN	En et al., Plasma immersion ion implantation reactor design considerations for oxide charging, 85 SURFACE AND COATINGS TECHNOLOGY 64-69 (1966).					
BEO	AO	Ku et al., The Application of Ion Beam Mixing, Doped Silicide, and Rapid Thermal Processing of Self-Aligned Silicide Technology, 137 J. Electrochem. Soc. No. 2, pp. 726-740 (February 1990).					
EXAMINER		DATE CONSIDERED					
BEO		11.22.04					
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U.S. PATENT DOCUMENTS							
*Examiner's Initials	Class	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
Beo	AA	5,670,298	09/97	Hur			
	AB	6,037,239	03/00	Jennings			
	AC	6,096,621	08/00	Jennings			
	AD	6,130,140	10/00	Gonzalez			
	AE	6,133,105	10/00	Chen et al.			
	AF	6,133,116	10/00	Kim et al.			
	AG	6,177,235 B1	01/01	Francou et al.			
	AH	6,277,709 B1	08/01	Wang et al.			
Beo	AI	6,277,728 B1	08/01	Ahn et al.			

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							Yes	No

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)		
Beo	AM	ABSTRACT: How to Eliminate Voiding in Porous-Low-k Dielectrics and The Mechanism of Void Formation; Lin et al.; 4 pages
Beo	AM	COB Stack DRAM Cell Technology beyond 100 nm Technology Node; Yongjik Park & Kinam Kim; pp. 349.1 - 349.3;
Beo	AO	Rubin et al., Shallow-Junction Diode Formation by Implantation of Arsenic and Boron Through Titanium-Silicide Films and ..., 17 IEEE Transactions on Electron Devices, No. 1, pp. 183-190 (January 1990).
<div style="display: flex; justify-content: space-between;"> <div>EXAMINER <i>Beth E. Owens</i></div> <div>DATE CONSIDERED <i>11-22-04</i></div> </div>		

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BEO	AA	6,440,793 B1	08/02	Divakaruni et al.	—		
	AB	6,465,325 B2	10/02	Ridley et al.	—		
	AC	6,720,638 B2	04/04	Tran	—		
	AD	6,780,728 B2	08/04	Tran	—		
	AE	6,156,674	12/00	Li et al.	—		
	AF	6,281,100 B1	08/01	Yin et al.	—		
	AG	6,291,363 B1	09/01	Yin et al.	—		
BEO	AH	6,380,611 B1	04/02	Yin et al.	—		
	AI	6,383,723 B1	05/02	Iyer et al.	—		

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<i>Beo</i>	AA	2001/0006759 A1	07/01	Shipley, Jr. et al.	—	—		
	AB	2002/0076879 A1	06/02	Lee et al.	—	—		
	AC	2002/0196651 A1	12/02	Weis	—	—		
	AD	2003/0013272 A1	01/03	Hong et al.	—	—		
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	AA	10/609,311		<del>Yates</del> <i>Yates</i> <i>Geo</i>			06/03
	AB	10/655,997		Dailey			09/03
	AC	10/690,029		Derderian et al.			10/03
	AD	10/882,118		Sandhu et al.			04/04
	AE	10/879,367		Blalock et al.			06/04
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		Document Number	Date	Country	Class	Subclass	Translation	
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BEO	AA	3,349,474	12/1963	D. H. Rauscher			
	AB	5,904,517	05/1999	Gardner et al.	438	197	
	AC	5,998,264	12/1999	Wu	438	260	
	AD	6,180,465 B1	01/2001	Gardner et al.	438	291	
	AE	6,207,485 B1	03/2001	Gardner et al.	438	216	
BEO	AF	6,548,854 B1	04/2003	Kizilyalli et al.	257	310	
	AG						
BEO	AH	2003/0045060 A1	03/2003	Ahn et al.	438	287	
	AI	2003/0045078 A1	03/2003	Ahn et al.	438	585	

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Document Number	Date	Country	Class	Subclass	Translation		
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BEO	AJ	EP 0 851 473 A2	01/1998	EPO	X		
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BEO	AM	Chang et al., Silicon surface treatments in advanced MOS gate processing, Microelectronic Engineering, (2004), pages 130-135
BEO	AN	Lemberger et al., Electrical characterization and reliability aspects of zirconium silicate films obtained from novel MOCVD precursors, Microelectronic Engineering (2004), pages 315-320
BEO	AO	Lu et al., Effects of the TaN <sub>x</sub> interface layer on doped tantalum oxide high-k films, VACUUM (2004), pages 1-9

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					Yes	No	

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Beo	AN	Singh et al., High and Low Dielectric Constant Materials, <i>The Electrochemical Society Interface</i> , Summer 1999, pages 26-30
	AD	
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Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	10/682,218		Basceri et al.			08/01/04
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